

HOKKAIDO UNIVERSITY

| Title | Thermogravimetric analysis and microstructural observations on the formation of GaN from the reaction between Ga2O3 and NH3 |
|------------------|---|
| Author(s) | Kiyono, Hajime; Sakai, Toshiki; Takahashi, Mari; Shimada, Shiro |
| Citation | Journal of Crystal Growth, 312(19), 2823-2827 https://doi.org/10.1016/j.jcrysgro.2010.06.021 |
| Issue Date | 2010-09-15 |
| Doc URL | http://hdl.handle.net/2115/44033 |
| Туре | article (author version) |
| File Information | JCG312-19_2823-2827.pdf |



Thermogravimetric analysis and microstructural observations on the formation of GaN from the reaction between Ga₂O₃ and NH₃

Hajime Kiyono*, Toshiki Sakai, Mari Takahashi, and Shiro Shimada Graduate School of Engineering, Hokkaido University, Sapporo, 060-8628, JAPAN

Abstract

Thermogravimetric analysis (TGA) and microstructural observations were carried to investigate the nitridation mechanism of β -Ga₂O₃ powder to GaN under an NH₃/Ar atmosphere. Non-isothermal TGA showed that nitridation of β -Ga₂O₃ starts at ~650 °C, followed by decomposition of GaN at ~1100 °C. Isothermal TGA showed that nitridation follows linear kinetics in the temperature range 800–1000 °C. At an early stage of nitridation, small GaN particles (~5 nm) are deposited on the β -Ga₂O₃ crystal surface, and they increase with time. We proposed a mechanism for the nitridation of Ga₂O₃ by NH₃ whereby nitridation of β -Ga₂O₃ proceeds via the intermediate vapor species Ga₂O (g). Keywords: A1, Growth models, A2. Growth from vapor, B1. Nitrides

PACS: 81.10.St Growth in controlled gaseous atmospheres

1. Introduction

Gallium nitride (GaN) is a promising wide-band gap semiconductor used in manufacturing light emitting diodes, laser diodes, and ultra-violet photo detectors. [1–3] GaN epilayers are usually fabricated by chemical vapor deposition using metal-organic gallium compounds. In general, such metal-organic compounds are expensive and difficult to handle in air, another method to fabricate GaN has been needed. It has been reported that GaN powders can be also prepared by nitridation of Ga₂O₃ by NH₃. [4–7] Recently, GaN epilayers, nanotubes, and nanobelts have been produced by this method. [8–11] In addition, bulk GaN crystals have been synthesized by carbothermal reduction and nitridation of β -Ga₂O₃ by NH₃. [12–15] These results indicate that the nitridation of Ga₂O₃ by NH₃ is an important method for fabricating GaN materials. The overall reaction for nitridation of Ga₂O₃ by NH₃ is as follows:

$$Ga_2O_3 + 2NH_3 \rightarrow 2GaN + 3H_2O$$
 (1)

Balkas et al. pointed out, on the basis of thermodynamic calculations, that reaction (1) does not occur directly but rather through intermediate gaseous species of Ga_2O (g). They suggested that GaN is formed by the reaction between NH₃ and the gaseous Ga₂O. [6] Luo et al. also suggested the formation of gaseous Ga₂O as an intermediate species by reaction between β -Ga₂O₃ and H-containing species that are formed by thermal decomposition of NH₃. Jung et al. suggested the nitridation of β -Ga₂O₃ by NH₃ proceeds via solid state species such as GaO_xN_y (s). [16, 17] From the previous studies, it can be concluded that the mechanism of Ga₂O₃ nitridation by NH₃ is still not clear. Usually, the kinetics of a chemical reaction provides information about its mechanism. The present study investigates the nitridation of β -Ga₂O₃ to GaN by NH₃ on the basis of kinetic results using thermogravimetric analysis (TGA) and microstructural observations; a nitridation mechanism is proposed.

2. Experimental procedures

2.1 β -Ga₂O₃ powder

Commercially available β -Ga₂O₃ powder (99.9% purity; Koujyundo Kagaku Co.) was used for the nitridation. Figure 1(a) shows the scanning electron microscopic (SEM) images of as-received β -Ga₂O₃ powder. The powder contains secondary particles about 1–10 μ m long consisting of primary particles of about 0.1 μ m in size. When as-received β -Ga₂O₃ powder was sintered at 1400 °C for 1 h in Ar, β -Ga₂O₃ powders were coarsened as a result of the growth of primary particles, accompanied by diminishing pore size (Fig. 1 (b)). The secondary particle sizes were almost same as those of the as-received powder. The sintered powder was also used for the nitridation. The specific surface area of the as-received and coarse β -Ga₂O₃ powder was about 10 and 1 m²/g, respectively, as measured by the BET method using N₂ gas (BELSORP-mini, BEL JAPAN,).

2.2 Thermogravimetric analysis and microstructural observations

The weight change during nitridation was continuously monitored by an electric micro balance (Cahn D200). The β -Ga₂O₃ powder was placed in an alumina cell, which was hung with alumina wires with about 40 cm long in total and located in a fused quartz tube in a vertical furnace. Mixed gases of NH₃/Ar (10/90, 50/50, 90/10 kPa), H₂/Ar (40/60 kPa), or Ar (100 kPa) at a total flow rate of 100 mL/min were introduced at the top of the tube. Nonisothermal nitridation was carried out by heating β -Ga₂O₃ to 1200 °C at a rate of 5 °C /min, while isothermal nitridation was carried out at a temperature 800-1000 °C for about 1 h. In the non-isothermal nitridation, the exhaust gas from the TG system was analyzed by a massspectrometer (VG GAS ANALYZER, FISONS). The sampling point of the exhaust gas was about 20 cm downstream from the sample holder, where the gas was cooled to room temperature. The nitrided samples from both non-isothermal and isothermal TGA were characterized by X-ray powder diffraction (XRD, RINT 2000, RIGAKU), SEM (JSM-6300F, JEOL), and high-resolution TEM-SEM (HD-2000, HITACHI). The residual oxygen in the sample was determined using an oxygen and nitrogen analyzer (EMGA-620W, HORIBA).

3. Results and Discussion

3.1 The results of thermogravimetrical analysis

Non-isothermal TGA results of as-received β -Ga₂O₃ powder obtained by heating to 1200 °C in NH₃/Ar (50/50 kPa), H₂/Ar (40/60 kPa), and Ar atmospheres are shown in Fig. 2. No weight change was observed in the Ar atmosphere over the entire temperature range (20–1200 °C); suggesting that vaporization of β -Ga₂O₃ powder does not occur in that temperature range. In H₂/Ar (40/60 kPa), the weight loss starts at ~800 °C. On the basis of thermodynamic calculations, Butto et al. suggested that Ga₂O (g) is formed as a main product above 720 °C by the reaction between Ga₂O₃(s) and H₂ given as follows:[18]

$$Ga_2O_3(s) + 2H_2(g) \rightarrow Ga_2O(g) + 2H_2O(g)$$
 (2)

Apparently, the weight loss in an H₂/Ar atmosphere is caused by the generation of Ga₂O (g) by partial decomposition or reduction of β -Ga₂O₃. In NH₃/Ar (50/50 kPa), the weight loss starts at ~650 °C and decreases to -10 wt%, reaching a short plateau at ~870°C (first weight loss). After the plateau, the weight decreases further, starting around 1000 °C, and becomes significant above 1100 °C (second weight loss). Figure 3 shows the XRD patterns for asreceived β -Ga₂O₃ powder and for the sample heated to 870 °C and 1200 °C in Ar/NH₃ (50/50 kPa). This indicates that β -Ga₂O₃ begins to change to a wurtzite-type GaN above 870 °C,

the latter becoming well-crystallized at 1200 °C. The weight loss due to the complete nitridation of β -Ga₂O₃ to GaN in Eq (1) is calculated to be -10.6%. A relatively good agreement between the first weight loss and the calculated one for the complete nitridation showed that the first weight loss is caused by the complete nitridation of β -Ga₂O₃ to GaN. The second weight loss after the plateau (>1000 °C) resulted from decomposition of GaN in NH₃. In the non-isothermal experiment in NH₃/Ar and H₂/Ar atmospheres, gas species containing Ga (> 69.7 in mass number) in the exhaust gas were not detected by the mass-spectroscopic analysis.

The kinetic results by isothermal TGA for the nitridation of as-received β -Ga₂O₃ powder in the temperature range 800–1000 °C are shown in Fig. 4. After the TG analysis, no deposit was observed at the outside wall of sample cell, hanging wires or inner wall of a furnace tube. Over this temperature range, the weight loss from -1% to -9% occurs linearly with time (dashed lines). The samples obtained at the weight loss of -10% over the entire temperature range gave only GaN peaks on XRD, indicating the nitridation of β -Ga₂O₃ by NH₃ according to Eq (1). The close-to-linear weight loss curve suggests that the nitridation is limited by an interfacial reaction.

 $\Delta W / W_{\text{theo}} \times 100 = kt \qquad (3)$

where, ΔW is the observed weight loss, W_{theo} the theoretical weight loss when the nitridation is completed (-10.6%), *k* the rate constant, and *t* the reaction time. From the slope of the linear region, *k* was calculated at each temperature. The Arrhenius plots of the *k* value provide activation energy of 110 kJ mol⁻¹ for nitridation reaction. The weight loss reduced after -9%, barely approaching the theoretical weight loss (-10.6%) due to the characteristic of complete nitridation. The sample obtained after the isothermal nitridation at 1000 °C actually contained about 4 wt% oxygen, suggesting the difficulty in complete removal of oxygen.

Figure 5(a) shows the weight loss by nitridation of β -Ga₂O₃ at various $P_{\rm NH3}$ at 800 °C. These results indicate that the weight loss proceeds linearly to $-8\% \sim -10.8\%$. The nitridation rate constant was calculated from the slope of the straight line approximation of the curves. A linear relationship exists between the rate constants and $P_{\rm NH3}$ (Fig. 5(b)). The nitridation of as-received and coarse β -Ga₂O₃ powders measured by isothermal TGA at 800 °C was compared (Fig. 6). At an early stage (0% to -3%), the nitridation rate for coarse β -Ga₂O₃ powder was slower than that of the as-received one; however, the two were almost the same at a middle stage (-3% to -8%). The surface area of the as-received β -Ga₂O₃ powder was about ten times larger than that of the coarse powder, hence the slower rates for the coarsened sample at the early stage is because of its smaller surface area.

3.2 Microstructural observation

Figure 7 shows SEM photographs of coarse β -Ga₂O₃ particles nitrided at various weight losses. The un-nitrided coarse β -Ga₂O₃ particles have a smooth surface with stepped hexagonal plates (Figs. 7 (a) and (a')). At -0.3% weight loss, very small particles (~5 nm) are formed on the surface of the coarse β -Ga₂O₃ particles (Figs. 7 (b) and (b')); the number and size of these particles on the coarse β -Ga₂O₃ increases with nitridation (Figs. 7(c)-(f)). Since the samples of -1.8 to -8.1% weight loss exhibited the GaN peaks in XRD, the deposited particles must be GaN. At -5.8 and -8.1% weight loss, the triangle rectangular particles are piled up on sloughs of Ga₂O₃, forming hollow or tubular aggregates GaN (Figs. 7(e) and (f)).

3.4 Nitridation mechanism

We propose, based on the kinetic results and microstructural observations, a nitridation mechanism consisting of four steps as shown in Fig. 8, in the temperature range of 800–1000 °C. First, Ga₂O (g) is formed by the reaction between β -Ga₂O₃ (s) and H₂ and/or H-containing reactive species formed by the thermal decomposition of NH₃ (Fig. 8 (a)). NH₃ is mostly decomposed to H₂ and N₂ at ~1000 °C under equilibrium conditions; however, a

previous study found that the decomposition of NH₃ was about 10% or lower at around 1000 °C in an open flow system.[19] Other studies suggest that some reactive intermediate species, such as H, NH, or NH₂ radicals, are formed during the thermal decomposition of NH₃. [6, 8] From non-isothermal TG results (Fig. 2), decomposition of β -Ga₂O₃ to Ga₂O(g) by H₂ (eq. 2) in an H₂/Ar (40/60 kPa) atmosphere starts above 800 °C, showing that H₂ and/or the reactive intermediate species containing H formed by thermal decomposition of NH₃ can react with β -Ga₂O₃ (s) to form Ga₂O (g). In the second step (Fig. 8 (b)), Ga₂O (g) reacts with NH₃ resulting in the deposition of nano-sized GaN particles on surface of the β -Ga₂O₃ particles given as follows:

 $Ga_2O(g) + 2NH_3 \rightarrow 2GaN + H_2O + 2H_2(4)$

The reaction (Eq. (4)) controls the nitridation of β -Ga₂O₃, as shown in Figs. 4 and 5, because the nitridation proceeds linearly with time and the nitridation rate depends linearly on *P* (NH₃). As nitridation progresses, the number and size of deposited GaN particles increases with the coagulated particles. At the third step (Fig. 8 (c)), such coagulated GaN particles are in triangular and rectangular shapes covering the starting β -Ga₂O₃ particles. H₂ and/or Hcontaining species are free to move into a Ga₂O₃ particle through GaN walls to form Ga₂O (g); however, the gas is confined inside GaN walls leading to an increase in the internal pressure. As a result of Ga_2O (g) escaping, the GaN forms tubes or hollows (Fig. 8 (d)). Once an exit is created, the reaction (Eq. (4)) proceeds linearly in proportion to P (NH₃). In this reaction sequence, Ga_2O is supposed to be instable at room temperature or to be transported in short distance, because gas species containing Ga was not detected in exhaust gas of TG system.

4. Summary

The kinetics of nitridation of β -Ga₂O₃ to wurtzite-type GaN in an NH₃/Ar atmosphere was studied by TGA and microstructural observation. Non-isothermal TGA, nitridation of β -Ga₂O₃ started at ~650 °C; followed by the decomposition of GaN at ~1100 °C. The kinetic results by isothermal TGA showed that the nitridation of Ga₂O₃ follows linear kinetics; suggesting that the rate-limiting step is an interfacial reaction. From microstructural observation, it was observed that nano-sized GaN particles were deposited on the surface β -Ga₂O₃ in an early stage, which increased with time, and that the coagulated GaN particles cover the Ga₂O₃ particles. We speculate that the reaction of β -Ga₂O₃ with H₂ and/or H containing species gas from NH₃ produces Ga₂O (g); the latter reacts with NH₃ to form GaN.

Acknowledgment

This work was supported in part by the Global COE Program (Project No. B01: Catalysis as the Basis for Innovation in Materials Science) from the Ministry of Education, Culture, Sports, Science and Technology, Japan)

References

- [1] R. P. Vaudo, D. Goepfert, T. D. Moustakas, D. M. Beyea, T. J. Frey and K. Meehan, J. Appl. Phys., 79(1996) 2779-2783.
- [2] G. Jacob and D. Bois, Appl. Phys. Lett., 30 (1977) 412-414.
- [3] S. J. Pearton and F. Ren, Advanced Materials, 12 (2000)1571.
- [4] A. Addamiano, J. Electrochem. Soc., 108 (1961) 1072-1072.
- [5] B. B. Binkowski and M. R. Lorent, J. Electrochem. Soc., 109 (1962) 24-26.
- [6] C. M. Balkas and R. F. Davis, J. Am. Ceram. Soc., 79[9] (1996) 2309-2312.
- [7] H. D. Xiao, H. L. Ma, C. S. Xue, J. Ma, F. J. Zong, X. J. Zhang, F. Ji and W. R. Hu, Mater. Chem. Phys., 88 (2004) 180-184.
- [8] L. Q. Luo, K. Yu, Z. Q. Zhu, Y. S. Zhang, H. L. Ma, C. S. Xue, Y. G. Yang and S. Q. Chen, *Mater. Lett*, 58 (2004)2893-2896.
- [9] S. Ohira, M. Yoshioka, T. Sugawara, K. Nakajima and T. Shishido, *Thin Solid Films*, 496 (2006) 53-57.
- [10] J. Dinesh, M. Eswaramoorthy and C. N. R. Rao, J. Phys. Chem. C, 111 (2007) 510-513.
- [11] H. J. Lee, T. I. Shin and D. H. Yoon, Surf. Coat. Tech., 202 (2008) 5497-5500.
- [12] S. Shimada and R. Taniguchi, J. Cryst. Growth, 263 (2004)1-3.

- [13] S. Shimada, Y. Miura, A. Miura and T. Sekiguchi, T. Cryst. Growth. Des., 7 (2007) 1251-1255.
- [14] A. Miura, S. Shimada, M. Yokoyama, H. Tachikawa and T. Kitamura, *Chem. Phys. Lett.*, 451 (2008) 222-225.
- [15] A. Miura, S. Shimada, T. Sekiguchi, M. Yokoyama and B. Mizobuchi, B. J. Cryst. Growth, 310 (2008) 530-535.
- [16] W. S. Jung, *Mater Lett*, **60** (2006) 2954-2957.
- [17] W. S. Jung, O. H. Han and S. A. Chae, *Mater. Chem. Phys.*, **100** (2006)199-202.
- [18] D. P. Butt, Y. Park and T. N. Taylor, J. Nucl. Mater., 264 (1999) 71-77.
- [19] H. Lee and J. S. Harris, J. Cryst. Growth, 169 (1996) 689-696.

Figures captions

Fig. 1. SEM photographs of (a) as-received and (b) coarse β -Ga₂O₃ powder. The coarsened sample was fabricated by heating as-received sample at 1400 °C for 1 h. Insets are magnified images.

Fig. 2. Non-isothermal TGA curves of as-received β -Ga₂O₃ powder against temperature in NH₃/Ar, H₂/Ar, and Ar atmospheres.

Fig. 3. XRD patterns of (a) as-received β -Ga₂O₃ and the sample obtained by non-isothermal nitridation up to (b) 870 °C and (c) 1200 °C.

Fig. 4. TGA curves obtained by isothermal experiments of β -Ga₂O₃ in Ar/NH₃ (50/50) atmosphere at the temperatures of (a) 800 °C, (b) 900 °C, and (c) 1000 °C. Dashed lines superimposed on the TGA curves show the slope of each curve. A horizontal dotted line shows the calculated weight loss based on the complete nitridation of β -Ga₂O₃.

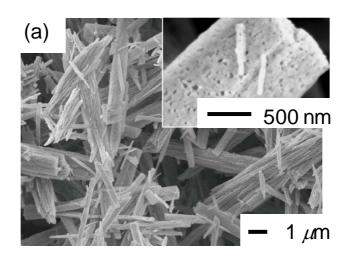
Fig. 5. (a) Isothermal TGA curves of the fine sample at 800 °C at various P(NH₃). Dashed

lines superimposed on the TGA curves show the slope of the each curve, and the horizontal dotted line, theoretical weight loss. (b) Plots of rate constants obtained from TGA results as a function of $P_{\rm NH3}$.

Fig. 6. Comparison of isothermal TGA curves between (a) as-received and (b) coarse β -Ga₂O₃ powder at 800 °C in Ar/NH₃ atmosphere. Dashed lines superimposed on the TGA curves show the slope of each curve. The horizontal dotted line shows the calculated weight loss based on the complete nitridation of Ga₂O₃.

Fig. 7. SEM photographs of partially nitrided coarse β -Ga₂O₃ powder at 800 °C. Weight changes of the partially nitrided samples are (a) 0%, (b) -0.3%, (c) -1.8%, (d) -3.5%, (e) -5.8%, and (f) -8.1%; (a'), (b'), and (f') are magnified images of (a), (b), and (f), respectively.

Fig. 8. A model for formation of GaN from β -Ga₂O₃ in an NH₃ atmosphere: (a) formation of Ga₂O (g), (b) formation of GaN depositions on β -Ga₂O₃; (c) growth of GaN; and (d) formation of hollow or tubular GaN aggregates.



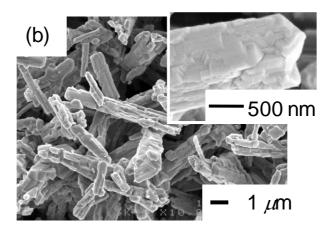


Fig. 1

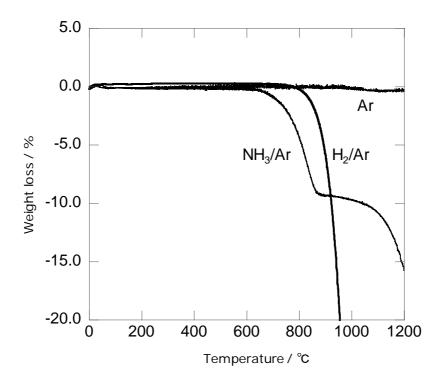


Fig.2

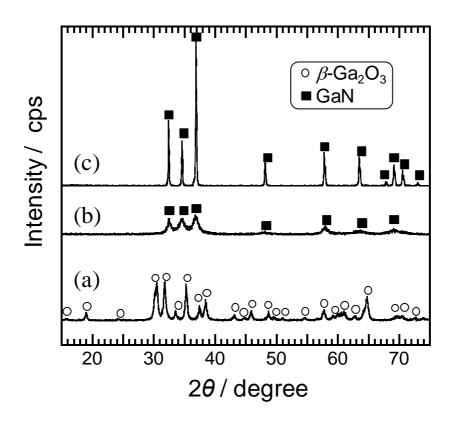


Fig.3

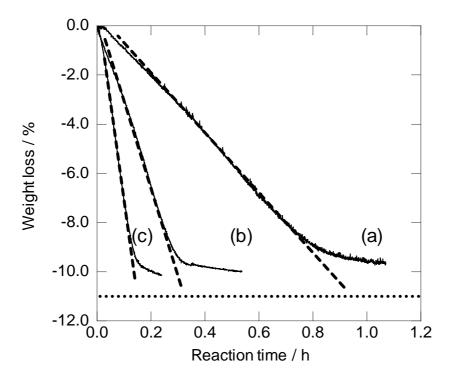


Fig.4

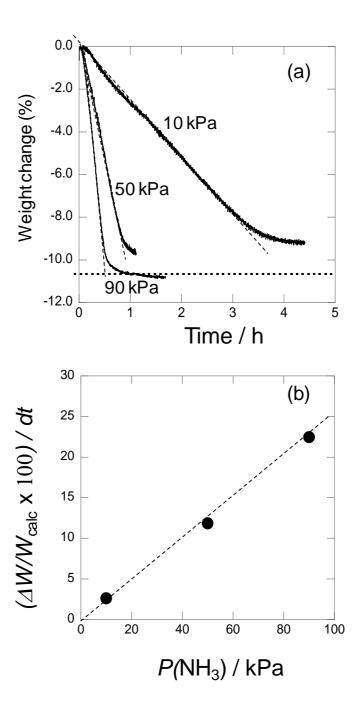


Fig.5

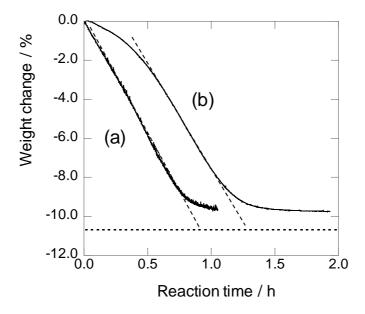


Fig.6

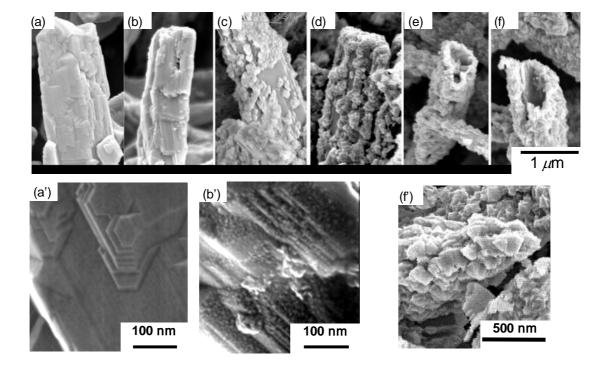


Fig.7

